

PTO-1449  <b>Information Disclosure Citation in an Application</b>		Application No.  10/661,873	Applicant(s)  Edgar Voelkl	
		Docket Number  068062.0167	Group Art Unit  2624	Filing Date  September 12, 2003

**U.S. PATENT DOCUMENTS**

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A.						
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**FOREIGN PATENT DOCUMENTS**

JP/	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	
JP/	L. 2307547	08/25/97	GB	G01N	21/88	X	
	M.						
	N.						
	O.						
	P.						

**NON-PATENT DOCUMENTS**

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
JP/	Q. Australian Patent Office Examination Report for Application No. SG 200501488-1 (4 pages)	06/27/06
	R.	
	S.	
	T.	
	U.	

EXAMINER	/Jayesh Patel/	DATE CONSIDERED
		05/04/2007

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
/JP/	A.	5404221	4/4/95	de Groot	356	349	2/24/93
/JP/	B.	5526116	6/11/96	de Groot	356	354	11/7/94
/JP/	C.	5671050	9/23/97	de Groot	356	359	12/28/94
/JP/	D.	5995224	11/30/99	de Groot	356	355	1/28/98
/JP/	E.	6249351	6/19/01	de Groot	356	512	6/3/99
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08-02-06

IFW

ATTORNEY DOCKET  
068062.0167

PATENT APPLICATION  
10/661,873



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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Edgar Voelkl  
Serial No.: 10/661,873  
Date Filed: September 12, 2003  
Group Art Unit: 2625  
Examiner: Couso, Yon Jung  
Title: **SYSTEM AND METHOD FOR DETECTING  
DIFFERENCES BETWEEN COMPLEX IMAGES**

MAIL STOP - AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

I hereby certify that this Information Disclosure Statement is being deposited with the United States Postal Service as Express Mail No. EV352403825US addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



Michael Wasaff  
8/11/06  
Date

Dear Sir:

**INFORMATION DISCLOSURE STATEMENT**

Applicant respectfully requests, pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, that the references listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. Copies of the references are enclosed for the Examiner's convenience. Furthermore, pursuant to 37 C.F.R. §§1.97(g) and (h), no representation is made that these references are material to the patentability of the present application.

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068062.0167

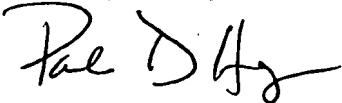
PATENT APPLICATION  
10/661,873

2

Applicant believes no fees are due, however, the Commissioner is hereby authorized to charge any fees to Deposit Account No. 50-2148 of Baker Botts L.L.P. in order to effectuate this filing.

Respectfully submitted,

BAKER BOTTS L.L.P.  
Attorneys for Applicant



Paula D. Heyman  
Reg. No. 48,363

Date: July 27, 2006

Correspondence Address:

Customer No. **31625**

512.322.2581  
512.322.8328 (Fax)

PTO-1449 O P E Information Disclosure Citation in an Application MAR 16 2006 PATENT & TRADEMARK OFFICE			Application No. 10/661,873	Applicant(s) Edgar Voelkl		
			Docket Number 068062.0167	Group Art Unit 2625	Filing Date September 12, 2003	
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/JP/s.	Australian Written Opinion; SG 200501488-1; Pgs.5					Mailing Date 1/18/06
T.						
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V.						
EXAMINER /Jayesh Patel/				DATE CONSIDERED 05/04/2007		
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 FEB 02 2005		10/661,873	Edgar Voelkl	
		Docket Number	Group Art Unit	Filing Date
		068062.0167	2625	September 12, 2003

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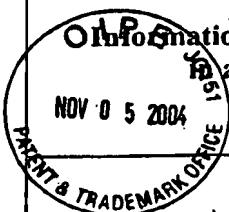
## NON-PATENT DOCUMENTS

		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
/JP/	O.	International Search Report for PCT/US03/28877, 8 pages	Mailed 12/28/04
/JP/	P.	Lindlein, et al., <i>Axicon-Type Test Interferometer for Cylindrical Surfaces: Systematic Error Assessment</i> , Applied Optics, Vol. 36, No. 13, pp. 2791-2795	5/1/97
/JP/	Q.	Q. Fu, et al., <i>Correction of Aberrations of an Electron Microscope by Means of Electron Holography</i> , The American Physical Society, Vol. 67, No. 17, pp. 2319-2322	10/21/91
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EXAMINER	/Jayesh Patel/	DATE CONSIDERED	05/04/2007
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PTO-1449



Patent No.

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Applicant(s)

Edgar Voelkl

Docket Number

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							YES	NO
/JP	L.	196 46 702 A1	5/28/97	DE	G06K	9/62		X
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	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
/JP	O. PCT Invitation to Pay Additional Fees for International Application No. PCT/US03/28877, 6 pages	Mailing Date 10/13/04
/JP	P. C.E. Thomas Jr. et al., "Direct to digital holography for semiconductor wafer defect detection and review" Design, Process Integration, and Characterization for Microelectronics, vol. 4692, XP-002282790, pages 180-194	03/2002
/JP	Q. E. Volkl et al., "Practical Electron Holography: Applications of Advanced Hologram Processing Techniques to Materials Science Problems" Electron Holography, XP008031237, pages 103-116	08/31/94
	R.	
	S.	

EXAMINER /Jayesh Patel/

DATE CONSIDERED

05/04/2007

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PTO-1449		Application No.	Applicant(s)		
Information Disclosure Citation in an Application		Not yet assigned	Edgar Voelkl		
		Docket Number 068062.0167	Group Art Unit Not Yet Assigned	Filing Date September 12, 2003	

## U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
/JP/A	6,525,821	02/25/03	Thomas et al.	356	457	01/04/00
/JP/ B	6,078,392	06/20/00	Thomas et al.	356	348	06/11/97
/JP/ C	2003/0048957 A1	03/13/03	Dai et al.	382	260	09/07/01
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	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
/JP/ P	U.S. Patent Application Serial No. 09/949,423 entitled <i>System and Method for Registering Complex Images</i> filed by X. Long Dai, et al. on September 7, 2001. 25 Pages.	09/07/01
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